# International Rectifier

#### **Features**

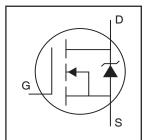
- Advanced Process Technology
- Ultra Low On-Resistance
- 175°C Operating Temperature
- Fast Switching
- Repetitive Avalanche Allowed up to Tjmax

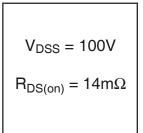
#### **Description**

Specifically designed for Industrial applications, this HEXFET® Power MOSFET utilizes the latest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of this design are a 175°C junction operating temperature, fast switching speed and improved repetitive avalanche rating . These features combine to make this design an extremely efficient and reliable device for use in Industrial applications and a wide variety of other applications.

# IRLR3110ZPbFIRLU3110ZPbF

HEXFET® Power MOSFET







#### **Absolute Maximum Ratings**

	Parameter	Max.	Units
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V (Silicon Limited)	63	
$I_D @ T_C = 100^{\circ}C$	Continuous Drain Current, V <sub>GS</sub> @ 10V (Silicon Limited)	45	Α
$I_D @ T_C = 25^{\circ}C$	Continuous Drain Current, V <sub>GS</sub> @ 10V (Package Limited)	42	
I <sub>DM</sub>	Pulsed Drain Current ①	250	Ī
P <sub>D</sub> @T <sub>C</sub> = 25°C	Power Dissipation	140	W
	Linear Derating Factor	0.95	W/°C
$V_{GS}$	Gate-to-Source Voltage	±16	V
E <sub>AS</sub> (Thermally limited)	Single Pulse Avalanche Energy <sup>②</sup>	110	mJ
E <sub>AS</sub> (Tested)	Single Pulse Avalanche Energy Tested Value ®	140	
I <sub>AR</sub>	Avalanche Current ①	See Fig.12a, 12b, 15, 16	Α
E <sub>AR</sub>	Repetitive Avalanche Energy ®		mJ
T <sub>J</sub>	Operating Junction and	-55 to + 175	
T <sub>STG</sub>	Storage Temperature Range		°C
	Reflow Soldering Temperature, for 10 seconds	300	
	Mounting Torque, 6-32 or M3 screw	10 lbf•in (1.1N•m)	

#### **Thermal Resistance**

	Parameter	Тур.	Max.	Units			
R <sub>eJC</sub>	Junction-to-Case ®		1.05				
$R_{\theta JA}$	Junction-to-Ambient (PCB mount) ⑦®		40	°C/W			
$R_{\theta JA}$	Junction-to-Ambient ®		110				

 $\label{eq:hexpectation} \mbox{HEXFET}^{\mbox{\scriptsize @}} \mbox{ is a registered trademark of International Rectifier}.$ 

## IRLR/U3110ZPbF

## Electrical Characteristics @ $T_J = 25$ °C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	100			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		0.077		V/°C	Reference to 25°C, I <sub>D</sub> = 1mA
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance		11	14	mΩ	V <sub>GS</sub> = 10V, I <sub>D</sub> = 38A ③
			12	16	Ī	V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 32A ③
V <sub>GS(th)</sub>	Gate Threshold Voltage	1.0		2.5	V	$V_{DS} = V_{GS}$ , $I_D = 100\mu A$
gfs	Forward Transconductance	52			S	$V_{DS} = 25V, I_D = 38A$
I <sub>DSS</sub>	Drain-to-Source Leakage Current			20	μΑ	$V_{DS} = 100V, V_{GS} = 0V$
				250	Ī	$V_{DS} = 100V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
I <sub>GSS</sub>	Gate-to-Source Forward Leakage			200	nA	V <sub>GS</sub> = 16V
	Gate-to-Source Reverse Leakage			-200	ĺ	V <sub>GS</sub> = -16V
$Q_g$	Total Gate Charge		34	48		$I_D = 38A$
$Q_{gs}$	Gate-to-Source Charge		10		nC	$V_{DS} = 50V$
$Q_{gd}$	Gate-to-Drain ("Miller") Charge		15		ĺ	V <sub>GS</sub> = 4.5V ③
t <sub>d(on)</sub>	Turn-On Delay Time		24			$V_{DD} = 50V$
t <sub>r</sub>	Rise Time		110			$I_D = 38A$
t <sub>d(off)</sub>	Turn-Off Delay Time		33		ns	$R_G = 3.7\Omega$
t <sub>f</sub>	Fall Time		48		1	V <sub>GS</sub> = 4.5V ③
L <sub>D</sub>	Internal Drain Inductance		4.5			Between lead,
					nН	6mm (0.25in.)
L <sub>S</sub>	Internal Source Inductance		7.5		ĺ	from package
						and center of die contact
C <sub>iss</sub>	Input Capacitance		3980			$V_{GS} = 0V$
Coss	Output Capacitance		310		ĺ	$V_{DS} = 25V$
C <sub>rss</sub>	Reverse Transfer Capacitance		130		рF	f = 1.0MHz
C <sub>oss</sub>	Output Capacitance		1820			$V_{GS} = 0V, V_{DS} = 1.0V, f = 1.0MHz$
Coss	Output Capacitance		170		1	$V_{GS} = 0V, V_{DS} = 80V, f = 1.0MHz$
C <sub>oss</sub> eff.	Effective Output Capacitance		320		1	$V_{GS} = 0V, V_{DS} = 0V \text{ to } 80V  $

#### **Source-Drain Ratings and Characteristics**

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current			63		MOSFET symbol
	(Body Diode)				Α	showing the
I <sub>SM</sub>	Pulsed Source Current			250		integral reverse
	(Body Diode) ①					p-n junction diode.
$V_{SD}$	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C$ , $I_S = 38A$ , $V_{GS} = 0V$ ③
t <sub>rr</sub>	Reverse Recovery Time		34	51	ns	$T_J = 25$ °C, $I_F = 38A$ , $V_{DD} = 50V$
Q <sub>rr</sub>	Reverse Recovery Charge		42	63	nC	di/dt = 100A/µs ③
t <sub>on</sub>	Forward Turn-On Time	Intrinsi	turn-or	time is	negligib	le (turn-on is dominated by LS+LD)

# International TOR Rectifier

## IRLR/U3110ZPbF

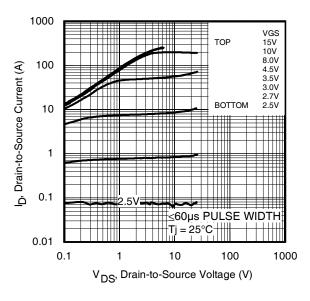


Fig 1. Typical Output Characteristics

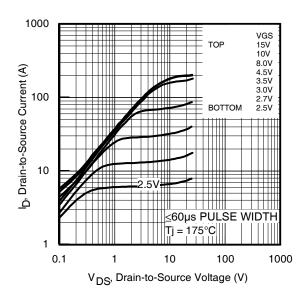


Fig 2. Typical Output Characteristics

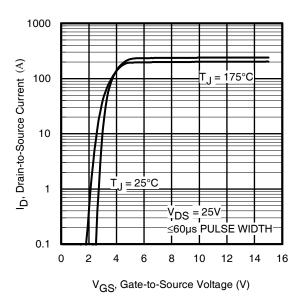


Fig 3. Typical Transfer Characteristics

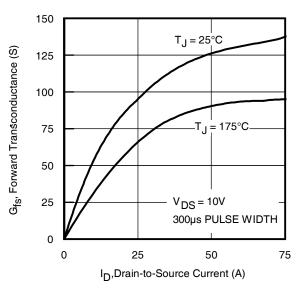
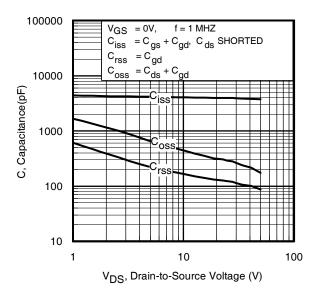
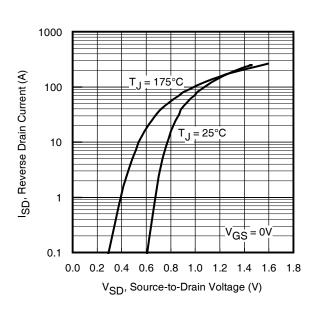


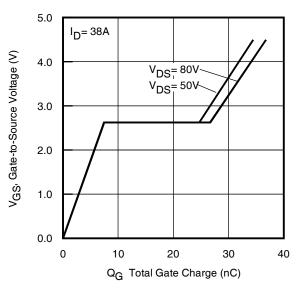
Fig 4. Typical Forward Transconductance vs. Drain Current



**Fig 5.** Typical Capacitance vs. Drain-to-Source Voltage



**Fig 7.** Typical Source-Drain Diode Forward Voltage



**Fig 6.** Typical Gate Charge vs. Gate-to-Source Voltage

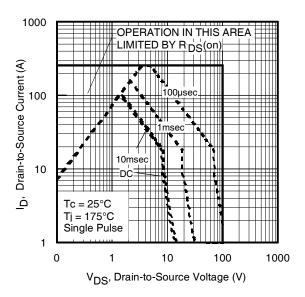
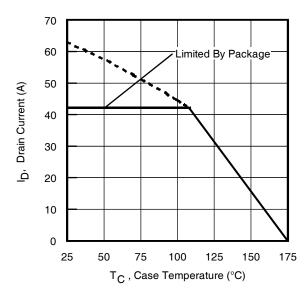


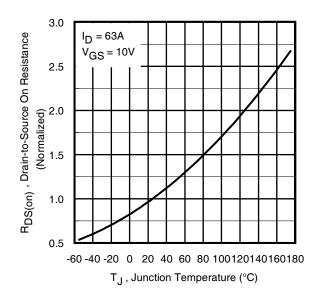
Fig 8. Maximum Safe Operating Area

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**Fig 9.** Maximum Drain Current vs. Case Temperature



**Fig 10.** Normalized On-Resistance vs. Temperature

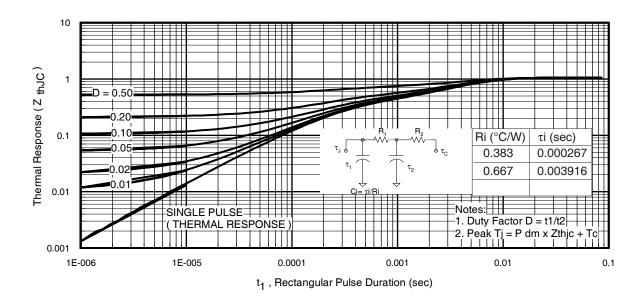


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

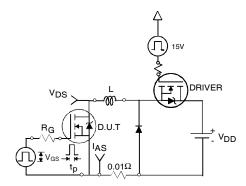


Fig 12a. Unclamped Inductive Test Circuit

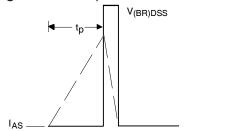


Fig 12b. | Unclamped Inductive Waveforms

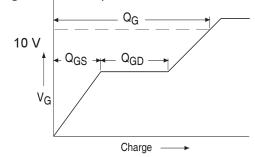
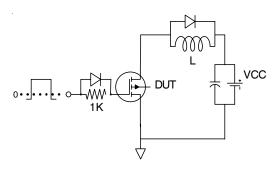
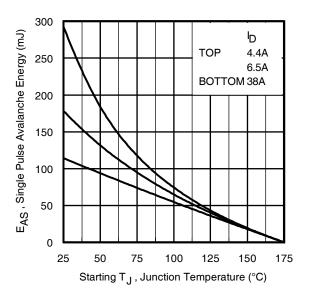


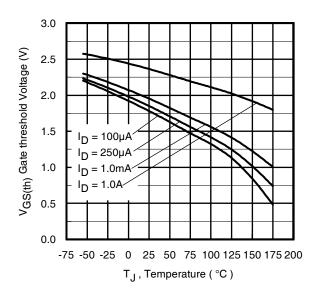
Fig 13a. Basic Gate Charge Waveform



**Fig 13b.** Gate Charge Test Circuit 6



**Fig 12c.** Maximum Avalanche Energy vs. Drain Current



**Fig 14.** Threshold Voltage vs. Temperature www.irf.com

## International TOR Rectifier

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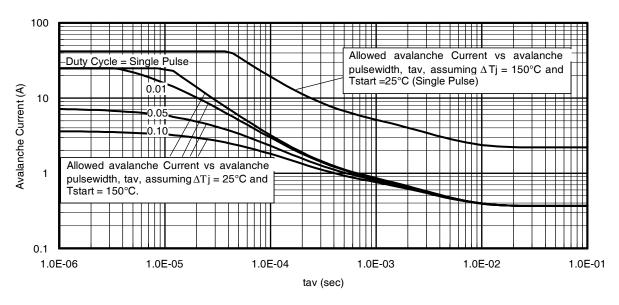
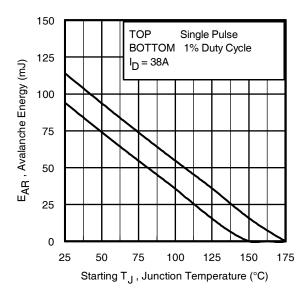


Fig 15. Typical Avalanche Current vs. Pulsewidth



**Fig 16.** Maximum Avalanche Energy vs. Temperature

## Notes on Repetitive Avalanche Curves, Figures 15, 16: (For further info, see AN-1005 at www.irf.com)

- Avalanche failures assumption:
   Purely a thermal phenomenon and failure occurs at a temperature far in excess of T<sub>jmax</sub>. This is validated for every part type.
- Safe operation in Avalanche is allowed as long as neither Tjmax nor lav (max) is exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 12a, 12b.
- 4. P<sub>D (ave)</sub> = Average power dissipation per single avalanche pulse.
- BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. I<sub>av</sub> = Allowable avalanche current.
- 7.  $\Delta T$  = Allowable rise in junction temperature, not to exceed  $T_{jmax}$  (assumed as 25°C in Figure 15, 16).  $t_{av}$  = Average time in avalanche. D = Duty cycle in avalanche =  $t_{av}$ ·f  $Z_{th,JC}(D, t_{av})$  = Transient thermal resistance, see figure 11)

$$\begin{split} P_{D \text{ (ave)}} &= 1/2 \text{ ( } 1.3 \cdot \text{BV} \cdot \text{I}_{av} \text{)} = \triangle \text{T/ } Z_{thJC} \\ \text{I}_{av} &= 2\triangle \text{T/ [ } 1.3 \cdot \text{BV} \cdot Z_{th} \text{]} \\ \text{E}_{AS \text{ (AR)}} &= P_{D \text{ (ave)}} \cdot t_{av} \end{split}$$

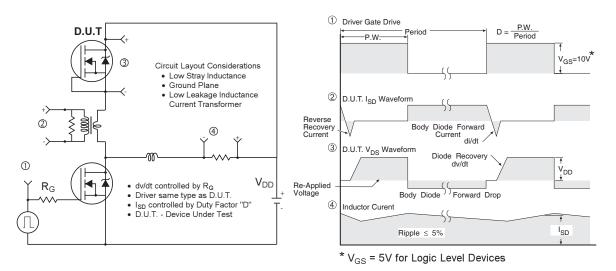


Fig 17. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

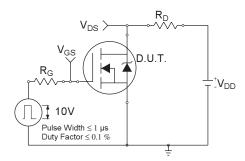


Fig 18a. Switching Time Test Circuit

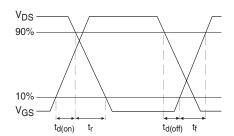
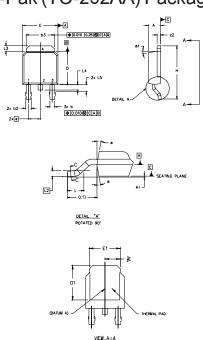


Fig 18b. Switching Time Waveforms

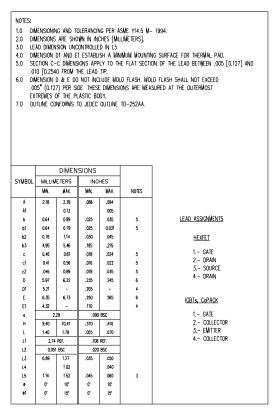
## International **TOR** Rectifier

## IRLR/U3110ZPbF

#### D-Pak (TO-252AA) Package Outline

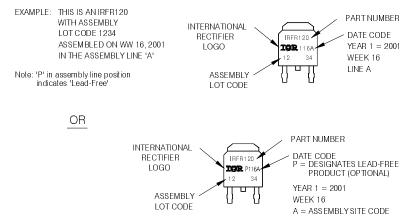


SECTION C-C



9

## D-Pak (TO-252AA) Part Marking Information

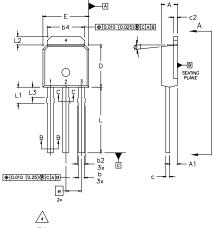


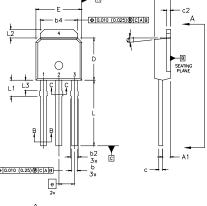
Note: For the most current drawing please refer to IR website at <a href="http://www.irf.com/package/">http://www.irf.com/package/</a> www.irf.com

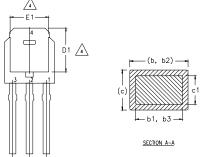
## IRLR/U3110ZPbF

#### International IOR Rectifier

#### I-Pak (TO-251AA) Package Outline







VIEW A-A

#### NOTES:

- DIMENSIONING AND TOLERANCING PER ASME Y14.5 M 1994.

  DIMENSION'S ARE SHOWN IN MILLIMETERS [INCHES].

  DIMENSION D & E DO NOT INCLUDE MOLD FLASH, MOLD FLASH SHALL NOT EXCEED 0.005" (0.127) PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.

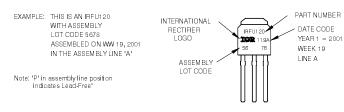
  THERMAL PAD CONTOUR OPTION WITHIN DIMENSION 64, L2, E1 & D1.
- LEAD DIMENSION UNCONTROLLED IN L3,
- DIMENSION 61, 63 APPLY TO BASE METAL ONLY. OUTLINE CONFORMS TO JEDEC OUTLINE TO-251AA, CONTROLLING DIMENSION: INCHES,

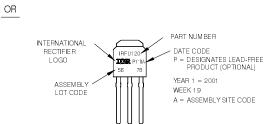
#### LEAD ASSIGNMENTS

HEXFET 1.- GATE 2.- DRAIN 3.- SOURCE 4.- DRAIN

SYMBOL	MILLIM	MilliMeters		HES	
	MIN.	MAX.	MIN.	MAX.	NOTES
A	2.18	2.39	0.086	.094	
A1	0.89	1,14	0.035	0.045	
ь	0.64	0.89	0.025	0.035	
ь1	0.64	0.79	0.025	0.031	4
b2	0.76	1,14	0.030	0.045	
b3	0.76	1,04	0.030 0.041		
b4	5.00	5,46	0.195	0,215	4
c	0.46	0,61	0.018	0,024	
c1	0,41	0,56	0.016	0,022	
c2	.046	0.86	0.018	0.035	
D	5.97	6.22	0.235	0.245	3, 4
D1	5,21	-	0.205	-	4
E	6,35	6.73	0.250	0,265	3, 4
E1	4.32	-	0.170	-	4
e	2.29		0.090	BSC	
L	8.89	9.60	0.350	0.380	
L1	1,91	2,29	0.075	0.090	
L2	0.89	1,27	0.035	0.050	4
L3	1,14	1,52	0.045	0.060	5
ø1	or	15"	o o	15*	

#### I-Pak (TO-251AA) Part Marking Information



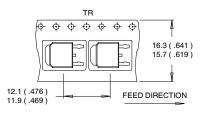


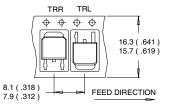
Note: For the most current drawing please refer to IR website at http://www.irf.com/package/

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#### D-Pak (TO-252AA) Tape & Reel Information

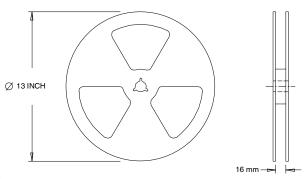
Dimensions are shown in millimeters (inches)





#### NOTES :

- CONTROLLING DIMENSION : MILLIMETER.
   ALL DIMENSIONS ARE SHOWN IN MILLIMETERS ( INCHES ).
- 3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



NOTES:
1. OUTLINE CONFORMS TO EIA-481.

#### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11).
- ② Limited by  $T_{Jmax}$ , starting  $T_{J} = 25^{\circ}C$ , L = 0.16mH $R_G = 25\Omega$ ,  $I_{AS} = 38A$ ,  $V_{GS} = 10V$ . Part not recommended for use above this value.
- ③ Pulse width  $\leq$  1.0ms; duty cycle  $\leq$  2%.
- 4 Coss eff. is a fixed capacitance that gives the same charging time as  $C_{\text{oss}}$  while  $V_{DS}$  is rising from 0 to 80% V<sub>DSS</sub>.
- Limited by  $T_{Jmax}$ , see Fig.12a, 12b, 15, 16 for typical repetitive avalanche performance.
- This value determined from sample failure population. 100% tested to this value in production.
- When mounted on 1" square PCB (FR-4 or G-10 Material).
- $R_{\theta}$  is measured at  $T_J$  approximately 90°C.

Data and specifications subject to change without notice. This product has been designed for the Industrial market. Qualification Standards can be found on IR's Web site.



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TAC Fax: (310) 252-7903

Visit us at www.irf.com for sales contact information.11/09

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